



双通道精度可调限流电源开关

查询样品: TPS2561-Q1

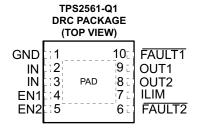
特性

- 符合汽车应用要求
- 2个分开的电流限制通道
- 满足 USB电流限制要求
- 可调电流限制, 250 mA-2.8 A (典型值)
- 2.8 A电流下的 +/- 7.5%电流限制精
- 快速过流响应 3.5 µS (典型值)
- 2个 44-mΩ 高侧金属氧化半导体场效应晶体管 (MOSFET)
- 工作范围: 2.5 V 至 6.5 V
- 2-µA 最大待机电源电流
- 内置软启动
- 15 kV/8 kV 系统级静电放电 (ESD) 能
- UL 列表 文件号 E169910
- 经认证的 CB 和 Nemko

说明

TPS2561-Q1是一款双通道配电开关,此开关适合于对电流限制精度有要求或者会遇到重电容负载和短路的应用。这些器件借助一个外部电阻器为每通道提供一个250 mA至2.8 A(典型值)间的可编程电流限制阀值。对电源开关的上升和下降次数进行控制以便在接通/切断期间大大降低电流浪涌。

当输出负载超过电流限制阀值时,通过切换到一个恒定电流模式,TPS2561-Q1器件的每个通道将输出电流限制在一个安全水平上。 在过流和过热情况下,每个通道的 FAULTx 逻辑输出独立低电平有效。



ENx = Active Low for the TPS2560 ENx = Active High for the TPS2561-Q1

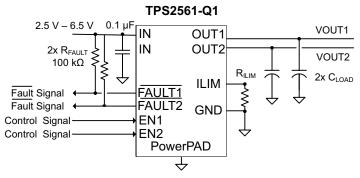


Figure 1. Typical Application as USB Power Switch

	GENERAL SWITCH CATALOG									
33 mΩ single 175201×A 0.2 A - 2 A 175202× 0.2 A - 2 A 175203× 0.2 A - 2 A	80 mΩ, single 1PS2014 600 mA 1PS2015 1A 1PS2015 500 mA 1PS2045 500 mA 1PS2049 100 mA 1PS2049 100 mA 1PS20501 1A 1PS2065 1 1A 1PS2066 1 1A 1PS2068 1.5 A 1PS2068 1.5 A	80 mΩ, dual TPS20428 500 mA TPS20528 500 mA TPS20528 550 mA TPS2062 1 A TPS2066 1 A TPS2066 1.5 A TPS2066 1.5 A	80 mΩ, dual TPS2080 500 mA TPS2081 500 mA TPS2092 500 mA TPS2091 250 mA TPS2092 250 mA	80 mΩ, triple TPS2043B 500 mA TPS2043B 500 mA TPS2053B 500 mA TPS2057A 250 mA TPS2067 1 A TPS2067 1 A	TPS2044B 500 mA	80 mΩ, quad TPS2085 500 mA TPS2086 500 mA TPS2095 500 mA TPS2095 250 mA TPS2096 250 mA TPS2097 250 mA				

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Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

ORDERING INFORMATION(1)

T _A ⁽²⁾	PACKAGE		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 125°C	SON - DRC	Reel of 3000	TPS2561QDRCRQ1	PXPQ

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.
- (2) Maximum ambient temperature is a function of device junction temperature and system level considerations, such as power dissipation and board layout. See *dissipation rating table* and *recommended operating conditions* for specific information related to these devices.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted (1) (2)

			VALUE	UNIT
,	Voltage	e range on IN, OUTx, ENx or ENx, ILIM, FAULTx	-0.3 to 7	V
,	Voltage	e range from IN to OUTx	–7 to 7	V
(Continu	uous output current	Internally Limited	
(Continu	uous total power dissipation	See the Dissipation Rating Table	
(Continuous FAULTx sink current		25	mA
ı	ILIM so	ource current	Internally Limited	mA
	TCD.	НВМ	2	kV
	ESD	CDM	1000	V
I	ESD – system level (contact/air) ⁽³⁾		8/15	kV
T _J I	Maximu	um junction temperature	-40 to 125 ⁽⁴⁾	°C

- (1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- 2) Voltages are referenced to GND unless otherwise noted.
- (3) Surges per EN61000-4-2, 1999 applied between USB and output ground of the TPS2561EVM (HPA424) evaluation module (documentation available on the web.) These were the test level, not the failure threshold.
- (4) Ambient over temperature shutdown threshold

DISSIPATION RATING TABLE

BOARD	PACKAGE	THERMAL RESISTANCE ⁽¹⁾ θ_{JA}	THERMAL RESISTANCE θ _{JC}	T _A ≤ 25°C POWER RATING
High-K ⁽²⁾	DRC	41.6°C/W	10.7°C/W	2403 mW

- 1) Mounting per the PowerPADTM Thermally Enhanced Package application report (SLMA002)
- (2) The JEDEC high-K (2s2p) board used to derive this data was a 3in × 3in, multilayer board with 1-ounce internal power and ground planes and 2-ounce copper traces on top and bottom of the board.



RECOMMENDED OPERATING CONDITIONS

		MIN	MAX	UNIT
V _{IN}	Input voltage, IN	2.5	6.5	V
V _{ENx}	Enable voltage	0	6.5	V
V _{IH}	High-level input voltage on ENx or ENx	1.1		
V _{IL}	Low-level input voltage on ENx or ENx		0.66	V
l _{OUTx}	Continuous output current per channel, OUTx	0	2.5	Α
	Continuous FAULTx sink current	0	10	mA
TJ	Operating virtual junction temperature	-40	125	°C
R _{ILIM}	Recommended resistor limit range	20	187	kΩ

ELECTRICAL CHARACTERISTICS

over recommended operating conditions, $V_{IENx} = 0 \text{ V}$, or $V_{ENx} = V_{IN}$ (unless otherwise noted)

	PARAMETER		TEST CON	NDITIONS ⁽¹⁾	MIN	TYP	MAX	UNIT
POWER	SWITCH				•		•	
_	Static drain-source on-state resistance per	T _J = 25 °C				44	50	0
r _{DS(on)}	channel, IN to OUTx ⁽²⁾	–40 °C ≤T _J ≤125 °C					79	mΩ
	Disc time output(2)	V _{IN} = 6.5 V			2	3	4	
t _r	Rise time, output ⁽²⁾	V _{IN} = 2.5 V	C _{Lx} = 1 μF	F, R_{Lx} = 100 Ω,	1	2	3	
	Fall time, output ⁽²⁾	V _{IN} = 6.5 V	(see Figu	re 2)	0.6	0.8	1	ms
t _f	Fail time, output	V _{IN} = 2.5 V			0.4	0.6	8.0	
ENABLE	INPUT EN OR EN	•						
	Enable pin turn on/off threshold				0.66		1.1	V
	Hysteresis					55 ⁽³⁾		mV
I _{EN}	Input current	$V_{ENx} = 0 \text{ V or } 6.5 \text{ V}, V_{/ENx} = 0 \text{ V or } 6.5 \text{ V}$			-0.5		0.5	μΑ
t _{on}	Turn-on time ⁽²⁾	$C_{Lx} = 1 \mu F$, $R_{Lx} = 100 \Omega$, (see Figure 2)					9	ms
t _{off}	Turn-off time ⁽²⁾						6	ms
CURREN	T LIMIT				·			
				$R_{ILIM} = 20 \text{ k}\Omega$	2590	2800	3005	
Ios	Current-limit threshold per channel (Maximu delivered to load) and Short-circuit current,			$R_{ILIM} = 61.9 \text{ k}\Omega$	800	900	1005	mA
	delivered to loady and erior eriodic editorit,			470	560	645		
t _{IOS}	Response time to short circuit	V _{IN} = 5.0 V (see Figur	re 3)	,		3.5 ⁽³⁾		μs

⁽¹⁾ Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.

⁽²⁾ Not production tested.

⁽³⁾ These parameters are provided for reference only, and do not constitute part of Tl's published specifications for purposes of Tl's product warranty.



ELECTRICAL CHARACTERISTICS (continued)

over recommended operating conditions, $V_{IENx} = 0 \text{ V}$, or $V_{ENx} = V_{IN}$ (unless otherwise noted)

	PARAMETER	TEST CO	ONDITIONS ⁽¹⁾	MIN	TYP	MAX	UNIT
SUPPLY (CURRENT			'		· ·	
I _{IN_off}	Supply current, low-level output	V _{IN} = 6.5 V, No load on OUTx,	$V_{\overline{ENx}} = 6.5 \text{ V or } V_{ENx} = 0 \text{ V}$		0.1	2	μΑ
	Complete support high laved sustaint	V 05 V No lood on OUT	$R_{ILIM} = 20 \text{ k}\Omega$		100	125	μA
I _{IN_on}	Supply current, high-level output	V _{IN} = 6.5 V, No load on OUT	R _{ILIM} = 100 kΩ		85	110	μA
I _{REV}	Reverse leakage current	V _{OUTx} = 6.5 V, V _{IN} = 0 V	T _J = 25°C		0.01	1	μA
UNDERVO	DLTAGE LOCKOUT						
UVLO	Low-level input voltage, IN	V _{IN} rising, T _J = 25°C			2.35	2.45	V
	Hysteresis, IN	$T_J = 25^{\circ}C$			35		mV
FAULTx F	LAG			•			
V_{OL}	Output low voltage, FAULTx	I FAULTX = 1 mA, FAULTX asser overcurrent condition	tion or de-assertion due to			180	mV
	Off-state leakage	V FAULTx = 6.5 V				1	μA
	FAULTx deglitch	I FAULTX = 1 mA, FAULTX asser overcurrent condition	tion or de-assertion due to	6	9	13	ms
THERMAL	SHUTDOWN					,	
OTSD2	Thermal shutdown threshold ⁽⁴⁾			155			°C
OTSD	Thermal shutdown threshold in current-limit (4)			135			°C
	Hysteresis				20(5)		°C

 ⁽⁴⁾ Not production tested.
 (5) These parameters are provided for reference only, and do not constitute part of TI's published specifications for purposes of TI's product

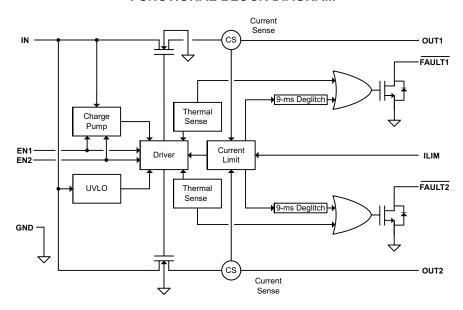


DEVICE INFORMATION

Pin Functions

PIN NAME NO.			DECODINE CONTRACTOR OF CONTRAC	
		I/O	DESCRIPTION	
EN1	-	I	Enable input, logic low turns on channel one power switch	
EN1	4	I	Enable input, logic high turns on channel one power switch	
EN2	-	I	Enable input, logic low turns on channel two power switch	
EN2	5	I	Enable input, logic high turns on channel two power switch	
GND	1		Ground connection; connect externally to PowerPAD	
IN	2, 3	I	Input voltage; connect a 0.1 μF or greater ceramic capacitor from IN to GND as close to the IC as possible.	
FAULT1	10	0	Active-low open-drain output, asserted during overcurrent or overtemperature condition on channel one.	
FAULT2	6	0	Active-low open-drain output, asserted during overcurrent or overtemperature condition on channel two	
OUT1	9	0	Power-switch output for channel one	
OUT2	8	0	Power-switch output for channel two	
ILIM	7	0	External resistor used to set current-limit threshold; recommended 20 k Ω \leq R _{ILIM} \leq 187 k Ω .	
PowerPAD™	PAD		Internally connected to GND; used to heat-sink the part to the circuit board traces. Connect PowerPAD to GND pin externally.	

FUNCTIONAL BLOCK DIAGRAM





PARAMETER MEASUREMENT INFORMATION

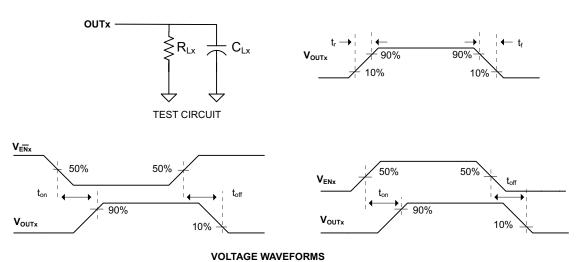


Figure 2. Test Circuit and Voltage Waveforms

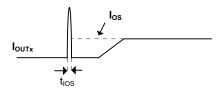


Figure 3. Response Time to Short Circuit Waveform

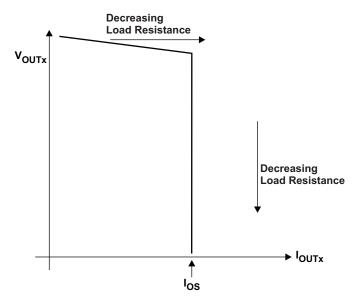


Figure 4. Output Voltage vs. Current-Limit Threshold



TYPICAL CHARACTERISTICS

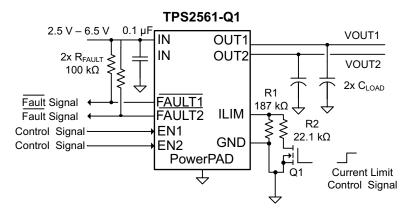


Figure 5. Typical Characteristics Reference Schematic

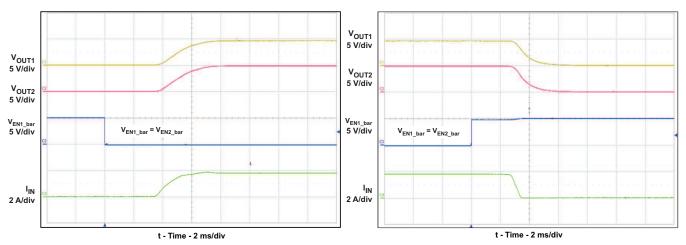


Figure 6. Turn-on Delay and Rise Time

Figure 7. Turn-off Delay and Fall Time

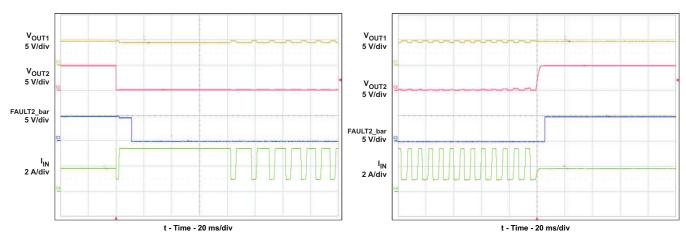


Figure 8. Full-Load to Short-Circuit Transient Response

Figure 9. Short-Circuit to Full-Load Recovery Response



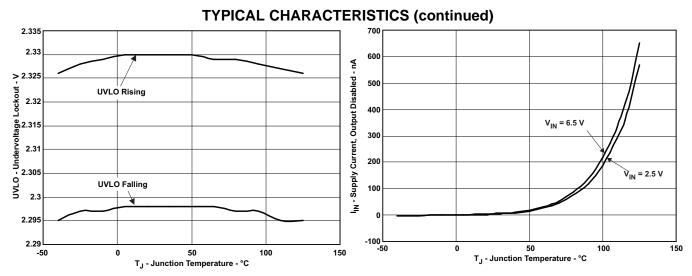


Figure 10. UVLO - Undervoltage Lockout - V

Figure 11. I_{IN} - Supply Current, Output Disabled - nA

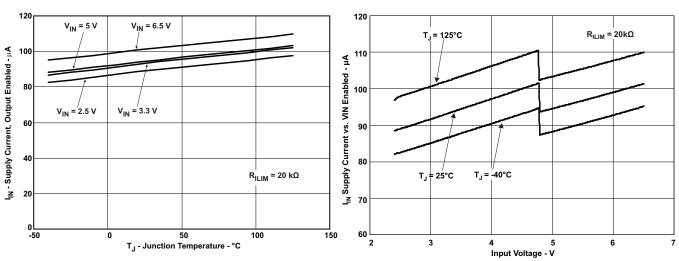


Figure 12. I_{IN} – Supply Current, Output Enabled – μA

0.6 0.5 - Static Drain-Source Current - A A = -40°C 0.4 T_A = 25°C = 125°C 0.3 0.2 S R_{ILIM} = 100 k Ω 100 150 200 150 V_{IN} - V_{OUT} - mV/div

Figure 13. I_{IN} – Supply Current, Output Enabled – μA

T_J - Junction Temperature - °C
Figure 14. MOSFET r_{DS(on)} vs. Junction Temperature

50

Figure 15. Switch Current vs. Drain-Source Voltage Across Switch

70

50

40

30

20

10

0

-50

 $_{r_{\text{Se}(\omega)}}$ - Static Drain-Source On-State Resistance - $m\Omega$



TYPICAL CHARACTERISTICS (continued)

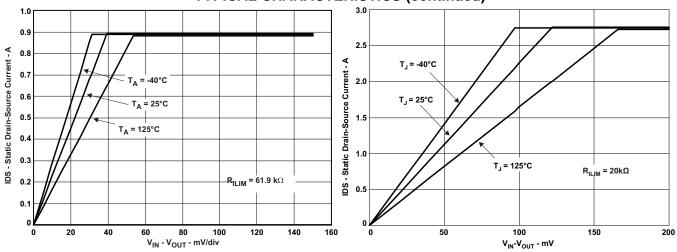


Figure 16. Switch Current vs. Drain-Source Voltage Across Switch

Figure 17. Switch Current vs. Drain-Source Voltage Across Switch



DETAILED DESCRIPTION

OVERVIEW

The TPS2561-Q1 is a dual-channel, current-limited power-distribution switch using N-channel MOSFETs for applications where short circuits or heavy capacitive loads are encountered. This device allows the user to program the current-limit threshold between 250 mA and 2.8 A (typ) per channel through an external resistor. This device incorporates an internal charge pump and gate drive circuitry necessary to drive the N-channel MOSFETs. The charge pump supplies power to the driver circuit for each channel and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 2.5 V and requires little supply current. The driver controls the gate voltage of the power switch. The driver incorporates circuitry that controls the rise and fall times of the output voltage to limit large current and voltage surges and provides built-in soft-start functionality. Each channel of the TPS2561-Q1 limits the output current to the programmed current-limit threshold I_{OS} during an overcurrent or short-circuit event by reducing the charge pump voltage driving the N-channel MOSFET and operating it in the linear range of operation. The result of limiting the output current to I_{OS} reduces the output voltage at OUTx because the N-channel MOSFET is no longer fully enhanced.

OVERCURRENT CONDITIONS

The TPS2561-Q1 responds to overcurrent conditions by limiting the output current per channel to I_{OS}. When an overcurrent condition is detected, the device maintains a constant output current and reduces the output voltage accordingly. Two possible overload conditions can occur.

The first condition is when a short circuit or partial short circuit is present when the device is powered-up or enabled. The output voltage is held near zero potential with respect to ground and the TPS2561-Q1 ramps the output current to I_{OS}. The TPS2561-Q1 devices will limit the current to I_{OS} until the overload condition is removed or the device begins to thermal cycle.

The second condition is when a short circuit, partial short circuit, or transient overload occurs while the device is enabled and powered on. The device responds to the overcurrent condition within time t_{IOS} (see Figure 3). The current-sense amplifier is overdriven during this time and momentarily disables the internal current-limit MOSFET. The current-sense amplifier recovers and ramps the output current to I_{OS} . Similar to the previous case, the TPS2561-Q1 device limits the current to I_{OS} until the overload condition is removed or the device begins to thermal cycle.

The TPS2561-Q1 thermal cycles if an overload condition is present long enough to activate thermal limiting in any of the above cases. The device turns off when the junction temperature exceeds 135°C (min) while in current limit. The device remains off until the junction temperature cools 20°C (typ) and then restarts. The TPS2561-Q1 cycles on and off until the overload is removed (see Figure 9) .



FAULTX RESPONSE

The FAULTx open-drain outputs are asserted (active low) on an individual channel during an overcurrent or overtemperature condition. The TPS2561-Q1 asserts the FAULTx signal until the fault condition is removed and the device resumes normal operation on that channel. The TPS2561-Q1 is designed to eliminate false FAULTx reporting by using an internal delay deglitch circuit (9-ms typ) for overcurrent conditions without the need for external circuitry. This ensures that FAULTx is not accidentally asserted due to normal operation such as starting into a heavy capacitive load. The deglitch circuitry delays entering and leaving current-limited induced fault conditions. The FAULTx signal is not deglitched when the MOSFET is disabled due to an overtemperature condition but is deglitched after the device has cooled and begins to turn on. This unidrectional deglitch prevents FAULTx oscillation during an overtemperature event.

UNDERVOLTAGE LOCKOUT (UVLO)

The undervoltage lockout (UVLO) circuit disables the power switch until the input voltage reaches the UVLO turnon threshold. Built-in hysteresis prevents unwanted on and off cycling due to input voltage droop during turn on.

ENABLE (ENX OR ENX)

The logic enables control the power switches and device supply current. The supply current is reduced to less than 2-µA when a logic high is present on ENx or when a logic low is present on ENx. A logic low input on ENx or a logic high input on ENx enables the driver, control circuits, and power switches. The enable inputs are compatible with both TTL and CMOS logic levels.

THERMAL SENSE

The TPS2561-Q1 self protects by using two independent thermal sensing circuits that monitor the operating temperature of the power switch and disable operation if the temperature exceeds recommended operating conditions. Each channel of the TPS2561-Q1 operates in constant-current mode during an overcurrent conditions, which increases the voltage drop across the power switch. The power dissipation in the package is proportional to the voltage drop across the power switch, which increases the junction temperature during an overcurrent condition. The first thermal sensor (OTSD) turns off the individual power switch channel when the die temperature exceeds 135°C (min) and the channel is in current limit. Hysteresis is built into the thermal sensor, and the switch turns on after the device has cooled approximately 20°C.

The TPS2561-Q1 also has a second ambient thermal sensor (OTSD2). The ambient thermal sensor turns off both power switch channels when the die temperature exceeds 155°C (min) regardless of whether the power switch channels are in current limit and will turn on the power switches after the device has cooled approximately 20°C. The TPS2561-Q1 continues to cycle off and on until the fault is removed.



APPLICATION INFORMATION

INPUT AND OUTPUT CAPACITANCE

Input and output capacitance improves the performance of the device; the actual capacitance should be optimized for the particular application. For all applications, a 0.1-µF or greater ceramic bypass capacitor between IN and GND is recommended as close to the device as possible for local noise decoupling. This precaution reduces ringing on the input due to power-supply transients. Additional input capacitance may be needed on the input to reduce voltage overshoot from exceeding the absolute maximum voltage of the device during heavy transient conditions. This is especially important during bench testing when long, inductive cables are used to connect the evaluation board to the bench power supply.

Output capacitance is not required, but placing a high-value electrolytic capacitor on the output pin is recommended when large transient currents are expected on the output.

PROGRAMMING THE CURRENT-LIMIT THRESHOLD

The overcurrent threshold is user programmable through an external resistor, R_{ILIM} . R_{ILIM} sets the current-limit threshold for both channels. The TPS2561-Q1 use an internal regulation loop to provide a regulated voltage on the ILIM pin. The current-limit threshold is proportional to the current sourced out of ILIM. The recommended 1% resistor range for R_{ILIM} is 20 k Ω \leq R_{ILIM} \leq 187 k Ω to ensure stability of the internal regulation loop. Many applications require that the minimum current limit is above a certain current level or that the maximum current limit is below a certain current level, so it is important to consider the tolerance of the overcurrent threshold when selecting a value for R_{ILIM} . The following equations calculates the resulting overcurrent threshold for a given external resistor value (R_{ILIM}). The traces routing the R_{ILIM} resistor to the TPS2561-Q1 should be as short as possible to reduce parasitic effects on the current-limit accuracy.

$$I_{OSmax} (mA) = \frac{52850 \text{ V}}{R_{ILIM}^{0.957} \text{ k}\Omega}$$

$$I_{OSnom} (mA) = \frac{56000 \text{ V}}{R_{ILIM} \text{ k}\Omega}$$

$$I_{OSmin} (mA) = \frac{61200 \text{ V}}{R_{ILIM}^{1.056} \text{ k}\Omega}$$
(1)

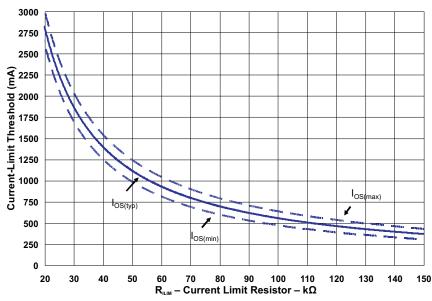


Figure 18. Current-Limit Threshold vs. R_{ILIM}



APPLICATION 1: DESIGNING ABOVE A MINIMUM CURRENT LIMIT

Some applications require that current limiting cannot occur below a certain threshold. For this example, assume that 2 A must be delivered to the load so that the minimum desired current-limit threshold is 2000 mA. Use the I_{OS} equations and Figure 18 to select R_{ILIM} .

$$I_{OSmin}$$
 (mA) = 2000 mA

$$I_{OSmin}$$
 (mA) = $\frac{61200 \text{ V}}{R_{ILIM}^{1.056} \text{ k}\Omega}$

$$R_{ILIM} (k\Omega) = \left(\frac{61200 \text{ V}}{I_{OSmin} \text{ mA}}\right)^{\frac{1}{1.056}}$$

$$R_{\rm ILIM} (k\Omega) = 25.52 k\Omega \tag{2}$$

Select the closest 1% resistor less than the calculated value: $R_{ILIM} = 25.5 \text{ k}\Omega$. This sets the minimum current-limit threshold at 2 A . Use the I_{OS} equations, Figure 18, and the previously calculated value for R_{ILIM} to calculate the maximum resulting current-limit threshold.

$$\begin{split} R_{\text{ILIM}} \; (k\Omega) &= 25.52 \; k\Omega \\ I_{\text{OSmax}} \; (\text{mA}) &= \frac{52850 \; \text{V}}{R_{\text{ILIM}}^{0.957} \; k\Omega} \\ I_{\text{OSmax}} \; (\text{mA}) &= \frac{52850 \; \text{V}}{25.5^{0.957} \; k\Omega} \\ I_{\text{OSmax}} \; (\text{mA}) &= 2382 \; \text{mA} \end{split}$$

The resulting maximum current-limit threshold is 2382 mA with a 25.5-k Ω resistor.

APPLICATION 2: DESIGNING BELOW A MAXIMUM CURRENT LIMIT

Some applications require that current limiting must occur below a certain threshold. For this example, assume that the desired upper current-limit threshold must be below 1000 mA to protect an up-stream power supply. Use the I_{OS} equations and Figure 18 to select R_{ILIM} .

$$I_{OSmax}$$
 (mA) = 1000 mA

$$I_{OSmax}$$
 (mA) = $\frac{52850 \text{ V}}{R_{ILIM}^{0.957} \text{ k}\Omega}$

$$R_{ILIM} (k\Omega) = \left(\frac{52850 \text{ V}}{I_{OSmax} \text{ mA}}\right)^{\frac{1}{0.957}}$$

$$R_{\rm ILIM} (k\Omega) = 63.16 k\Omega \tag{4}$$

Select the closest 1% resistor greater than the calculated value: R_{ILIM} = 63.4 k Ω . This sets the maximum current-limit threshold at 1000 mA . Use the I_{OS} equations, Figure 18, and the previously calculated value for R_{ILIM} to calculate the minimum resulting current-limit threshold.

$$R_{II IM} (k\Omega) = 63.4 k\Omega$$

$$I_{OSmin}$$
 (mA) = $\frac{61200 \text{ V}}{R_{ILIM}^{1.056} \text{ k}\Omega}$

$$I_{OSmin}$$
 (mA) = $\frac{61200 \text{ V}}{63.4^{1.056} \text{ k}\Omega}$

$$I_{OSmin}$$
 (mA) = 765 mA

The resulting minimum current-limit threshold is 765 mA with a 63.4-k Ω resistor.

(5)



ACCOUNTING FOR RESISTOR TOLERANCE

The previous sections described the selection of $R_{\rm ILIM}$ given certain application requirements and the importance of understanding the current-limit threshold tolerance. The analysis focused only on the TPS2561-Q1 performance and assumed an exact resistor value. However, resistors sold in quantity are not exact and are bounded by an upper and lower tolerance centered around a nominal resistance. The additional $R_{\rm ILIM}$ resistance tolerance directly affects the current-limit threshold accuracy at a system level. The following table shows a process that accounts for worst-case resistor tolerance assuming 1% resistor values. Step one follows the selection process outlined in the application examples above. Step two determines the upper and lower resistance bounds of the selected resistor. Step three uses the upper and lower resistor bounds in the $I_{\rm OS}$ equations to calculate the threshold limits. It is important to use tighter tolerance resistors, for example, 0.5% or 0.1%, when precision current limiting is desired.

Table 1. Common R_{ILIM} Resistor Selections

TELINI								
Desired Naminal	Ideal Desistes	Classet 40/	Resistor	Tolerance		Actual Limits		
Desired Nominal Current Limit (mA)	Ideal Resistor (kΩ)	Closest 1% Resistor (kΩ)	1% low (kΩ)	1% high (kΩ)	IOS MIN (mA)	IOS Nom (mA)	IOS MAX (mA)	
300	186.7	187	185.1	188.9	241.6	299.5	357.3	
400	140	140	138.6	141.4	328	400	471.4	
600	93.3	93.1	92.2	94	504.6	601.5	696.5	
800	70	69.8	69.1	70.5	684	802.3	917.6	
1000	56	56.2	55.6	56.8	859.9	996.4	1129.1	
1200	46.7	46.4	45.9	46.9	1052.8	1206.9	1356.3	
1400	40	40.2	39.8	40.6	1225	1393	1555.9	
1600	35	34.8	34.5	35.1	1426.5	1609.2	1786.2	
1800	31.1	30.9	30.6	31.2	1617.3	1812.3	2001.4	
2000	28	28	27.7	28.3	1794.7	2000	2199.3	
2200	25.5	25.5	25.2	25.8	1981	2196.1	2405.3	
2400	23.3	23.2	23	23.4	2188.9	2413.8	2633	
2600	21.5	21.5	21.3	21.7	2372.1	2604.7	2831.9	
2800	20	20	19.8	20.2	2560.4	2800	3034.8	



POWER DISSIPATION AND JUNCTION TEMPERATURE

The low on-resistance of the N-channel MOSFET allows small surface-mount packages to pass large currents. It is good design practice to estimate power dissipation and junction temperature. The below analysis gives an approximation for calculating junction temperature based on the power dissipation in the package. However, it is important to note that thermal analysis is strongly dependent on additional system level factors. Such factors include air flow, board layout, copper thickness and surface area, and proximity to other devices dissipating power. Good thermal design practice must include all system level factors in addition to individual component analysis.

Begin by determining the $r_{DS(on)}$ of the N-channel MOSFET relative to the input voltage and operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read $r_{DS(on)}$ from the typical characteristics graph. Using this value, the power dissipation can be calculated by:

$$P_D = (R_{DS(on)} \times I_{OUT1}^2) + (R_{DS(on)} \times I_{OUT2}^2)$$

Where:

P_D = Total power dissipation (W)

 $r_{DS(on)}$ = Power switch on-resistance of one channel (Ω)

 I_{OUTx} = Maximum current-limit threshold set by $R_{ILIM}(A)$

This step calculates the total power dissipation of the N-channel MOSFET.

Finally, calculate the junction temperature:

$$T_{J} = P_{D} \times \theta_{JA} + T_{A}$$

Where:

 T_A = Ambient temperature (°C)

 θ_{JA} = Thermal resistance (°C/W)

P_D = Total power dissipation (W)

Compare the calculated junction temperature with the initial estimate. If they are not within a few degrees, repeat the calculation using the refined $r_{DS(on)}$ from the previous calculation as the new estimate. Two or three iterations are generally sufficient to achieve the desired result. The final junction temperature is highly dependent on thermal resistance θ_{JA} , and thermal resistance is highly dependent on the individual package and board layout. The Dissipating Rating Table provides example thermal resistances for specific packages and board layouts.



AUTO-RETRY FUNCTIONALITY

Some applications require that an overcurrent condition disables the part momentarily during a fault condition and re-enables after a pre-set time. This auto-retry functionality can be implemented with an external resistor and capacitor. During a fault condition, FAULTx pulls ENx low disabling the part. The part is disabled when ENx is pulled below the turn-off threshold, and FAULTx goes high impedance allowing C_{RETRY} to begin charging. The part re-enables when the voltage on ENx reaches the turn-on threshold, and the auto-retry time is determined by the resistor/capacitor time constant. The part will continue to cycle in this manner until the fault condition is removed.

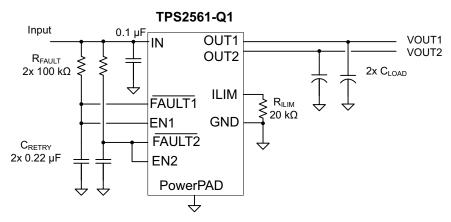


Figure 19. Auto-Retry Functionality

Some applications require auto-retry functionality and the ability to enable or disable with an external logic signal. The figure below shows how an external logic signal can drive EN through R_{FAULT} and maintain auto-retry functionality. The resistor/capacitor time constant determines the auto-retry time-out period.

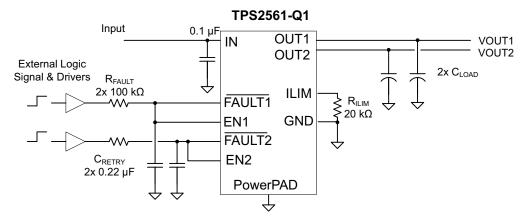


Figure 20. Auto-Retry Functionality With External EN Signal



TWO-LEVEL CURRENT-LIMIT CIRCUIT

Some applications require different current-limit thresholds depending on external system conditions. Figure 21 shows an implementation for an externally controlled, two-level current-limit circuit. The current-limit threshold is set by the total resistance from ILIM to GND (see previously discussed *Programming the Current-Limit Threshold* section). A logic-level input enables or disables MOSFET Q1 and changes the current-limit threshold by modifying the total resistance from ILIM to GND. Additional MOSFET and resistor combinations can be used in parallel to Q1 and R2 to increase the number of additional current-limit levels.

NOTE

ILIM should never be driven directly with an external signal.

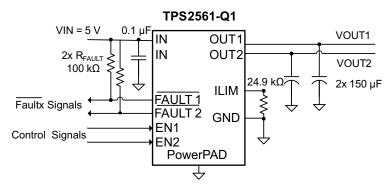


Figure 21. Two-Level Current-Limit Circuit



REVISION HISTORY

Cr	nanges from Original (December 2011) to Revision A	Page
•	Changed part number from TPS2561 to TPS2561-Q1 in all images where part number appears	2
•	Changed the First 2 rows of TYP and MAX columns of the ELEC CHAR table from 110 / 290 to 44 / 50, second row 320 / 79 and added cross reference to second column 'Not producton tested.'	

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
TPS2561QDRCRQ1	Active	Production	VSON (DRC) 10	3000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 125	PXPQ
TPS2561QDRCRQ1.B	Active	Production	VSON (DRC) 10	3000 LARGE T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 125	PXPQ

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF TPS2561-Q1:

Catalog: TPS2561

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

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NOTE: Qualified Version Definitions:

 $_{\bullet}$ Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

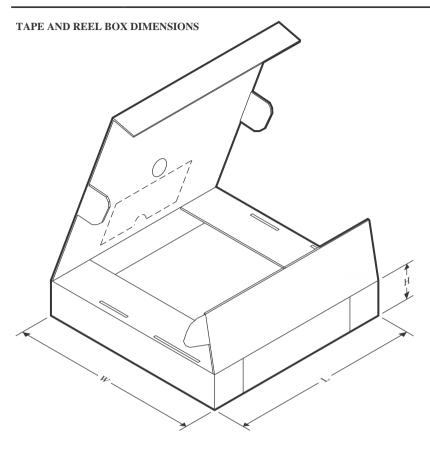


*All dimensions are nominal

Device		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS2561QDRCRQ1	VSON	DRC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

PACKAGE MATERIALS INFORMATION

www.ti.com 23-Jul-2025



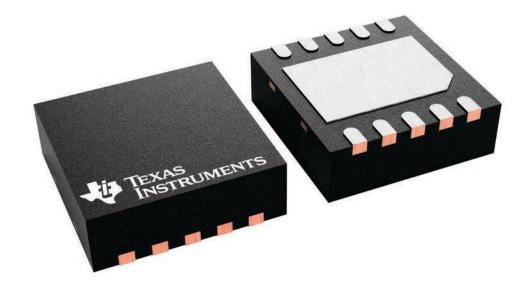
*All dimensions are nominal

	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
ı	TPS2561QDRCRQ1	VSON	DRC	10	3000	353.0	353.0	32.0	

3 x 3, 0.5 mm pitch

PLASTIC SMALL OUTLINE - NO LEAD

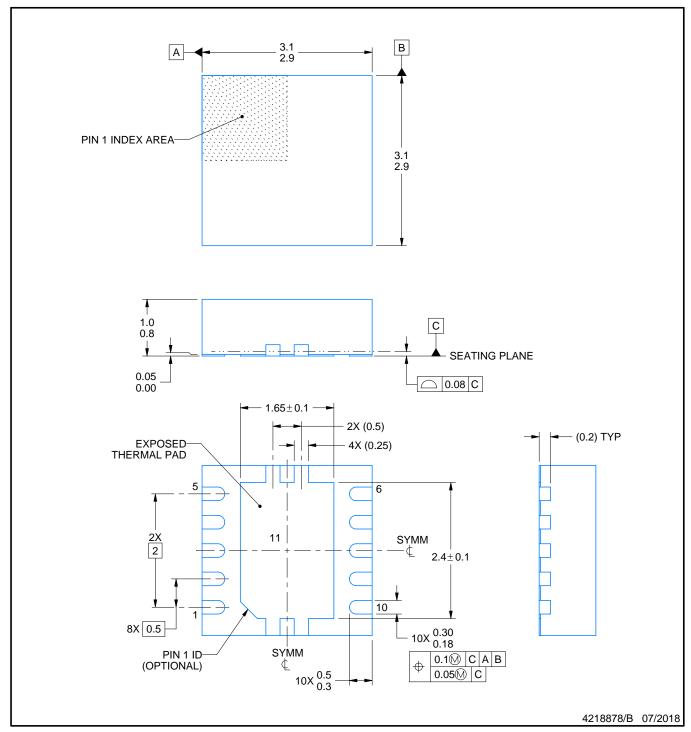
This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC SMALL OUTLINE - NO LEAD

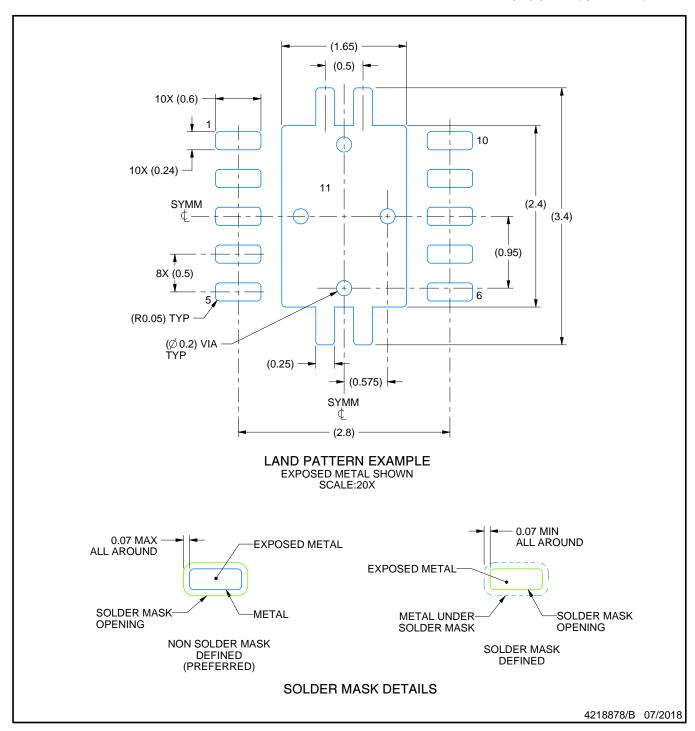


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC SMALL OUTLINE - NO LEAD

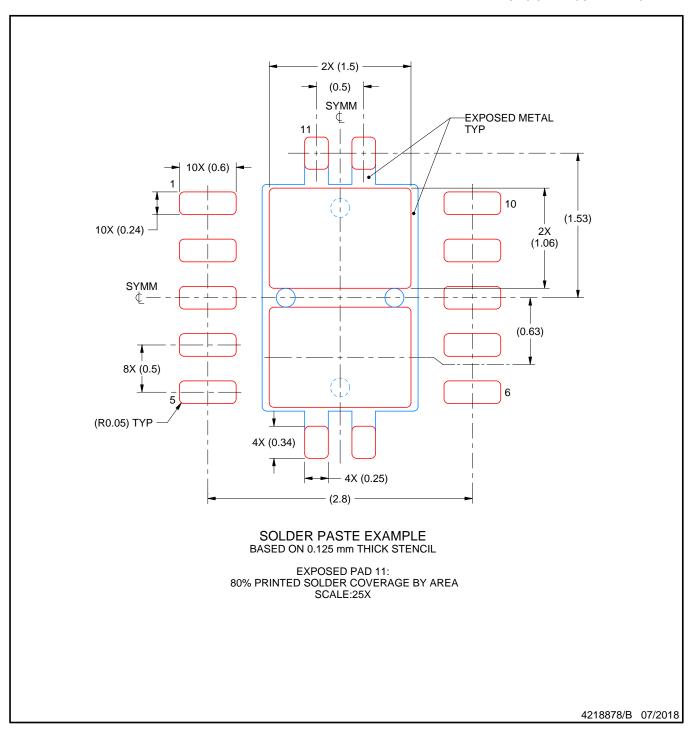


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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